

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10736698	CHEN ET AL.
	Examiner	Art Unit
	GERMAN VIANA DI PRISCO	2617

SEARCHED

Class	Subclass	Date	Examiner
See application file for complete search history		6/9/2010	GV

SEARCH NOTES

Search Notes	Date	Examiner
EAST Image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (see attached search strategy)	4/3/2008	GV
Inventor name and Assignee search in PALM ExPO and EAST	4/3/2008	GV
EPO Database(http://ep.espacenet.com)	4/3/2008	GV
Consulted with Rafael Perez-Gutierrez	4/3/2008	GV
Updated search	6/9/2010	GV

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
See interference search in search history		6/9/2010	GV

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